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Correction to "Energy dissipation in multifrequency atomic force microscopy"

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Correction

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In the section "Energy dissipation" of the above manuscript, there is a typesetting error in the mathematical expressions after Equation 5. The correct form must be:

The energy balance of each decaying mode obtained from Equation 4 in the time window $0 < t < \tau = 200$ µs (see Figure 1) can be written as

$$E_{b_i} = E_{\gamma_i} \tag{5}$$

where

$$E_{b_i} = \Delta K_i + \Delta U_i$$

$$E_{\gamma_i} = \int_0^\tau m_{\mathrm{eq}} \gamma_i v_i^2 dt$$

i is the index of the mode, $\Delta K_i = 1/2\ m_{\mathrm{eq}}(\mathrm{v}_i(0)^2 - \mathrm{v}_i(\tau)^2)$ is the variation of kinetic energy, and $\Delta U_i = 1/2\ k_i(z_i(0)^2 - z_i(\tau)^2)$ is the variation of elastic potential energy.